

Application/Control No.	Applicant(s)/Patent Reexamination	Applicant(s)/Patent under Reexamination	
10/700,243	SIMSKE, STEVEN J.		
Examiner	Art Unit		
CHONG H NGUYEN	3661		

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated WEST/DERWENT	12/7/2007	CHN		
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